Supporting Information

The introduction of perovskite seed layer for high performance perovskite solar cells

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Figure S1. Energy band diagram of perovskite solar cells.



Figure S2. XPS survey spectrum of PTAA control, Pbl₂ seed layer and CSPL films after washing by DMF solvent.



Figure S3. EQE and calculated J_{sc} of p-i-n structure and n-i-p structure of CSPL perovskite solar cells. (p-i-n w/o CSPL:17.25 Jsc(mAcm⁻²), p-i-n w/ CSPL: 20.05 Jsc(mAcm⁻²), n-i-p w/o CSPL: 21.13 Jsc(mAcm⁻²), n-i-p w/ CSPL: 22.90 Jsc(mAcm⁻²))



Figure S4. *J-V* charcteristics of perovksite solar cells without and with CSPL based on PEDOT:PSS HTL.

Table S1. Solar cells characteristic of p-i-n structure perovskite devices without and with an	d
without CSPL based on PEDOT:PSS HTL.	

	J _{sc} (mA cm ⁻²)	<i>V</i> _{oc} (V)	FF	PCE (%)
w/o S.L.	18.39	0.93	0.75	12.81
w/ S.L.	20.09	1.00	0.79	16.25



Figure S5. Histogram of device statistics from a total of 30 p-i-n structure solar cell devices (ITO/PTAA/seed layer/MAPbBr_xI_{3-x}/PC₆₁BM/AI) comprising without and with CSPL. (a) Short circuit current density, (b) open circuit voltage, (c) fill factor.



Figure S6. Histogram of n-i-p device statistics from a total of 30 solar cell devices (FTO/bl-TiO₂/Mesoprous TiO₂+Perovskite((FAPbI₃)_{0.85}(MAPbBr₃)_{0.15})/Spiro-MeOTAD/Au) comprising without and with CSPL. (a) Short circuit current density, (b) open circuit voltage, (c) fill factor



Figure S7. Atomic force microscope (AFM) surface image of PEDOT control substrate, Pbl₂, CSPL films respectively, after washed by DMF solvent.



Figure S8. Stability test was performed for non-encapsulated cells (with and without CSPL PeSCs) under an air about 40% humidity condition.